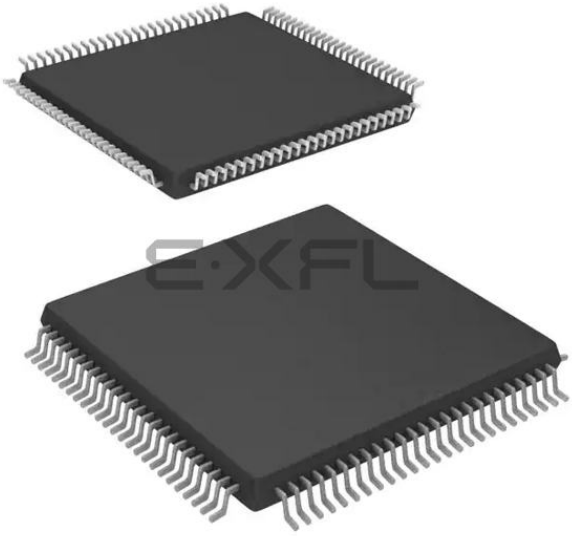


Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	200
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	80
Number of Gates	1500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1415a-1vqg100m

ACT 3 Family Overview

Detailed Specifications

Package Pin Assignments

Datasheet Information

1 – ACT 3 Family Overview

General Description

Microsemi's ACT 3 Accelerator Series of FPGAs offers the industry's fastest high-capacity programmable logic device. ACT 3 FPGAs offer a high performance, PCI compliant programmable solution capable of 186 MHz on-chip performance and 9.0 nanosecond clock-to-output (–1 speed grade), with capacities spanning from 1,500 to 10,000 gate array equivalent gates.

The ACT 3 family builds on the proven two-module architecture consisting of combinatorial and sequential logic modules used in Microsemi's 3200DX and 1200XL families. In addition, the ACT 3 I/O modules contain registers which deliver 9.0 nanosecond clock-to-out times (–1 speed grade). The devices contain four clock distribution networks, including dedicated array and I/O clocks, supporting very fast synchronous and asynchronous designs. In addition, routed clocks can be used to drive high fanout signals such as flip-flop resets and output.

The ACT 3 family is supported by Microsemi's Designer Series Development System which offers automatic placement and routing (with automatic or fixed pin assignments), static timing analysis, user programming, and debug and diagnostic probe capabilities.

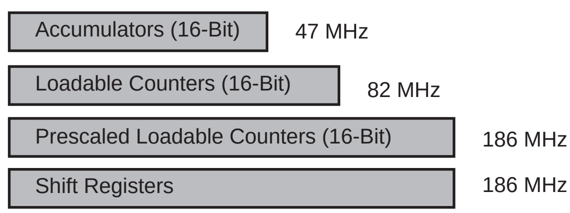
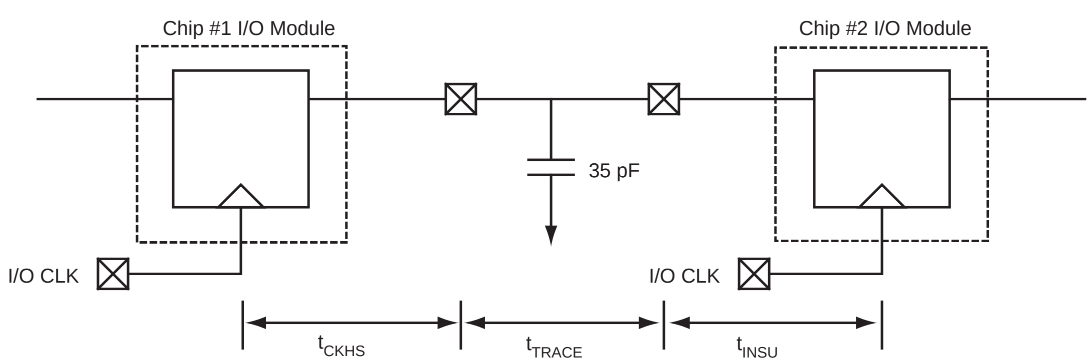


Figure 1-1 • **Predictable Performance (worst-case commercial, –1 speed grade)**

System Performance Model



Logic Modules

ACT 3 logic modules are enhanced versions of the 1200XL family logic modules. As in the 1200XL family, there are two types of modules: C-modules and S-modules (Figure 2-2 and Figure 2-3). The C-module is functionally equivalent to the 1200XL C-module and implements high fanin combinatorial macros, such as 5-input AND, 5-input OR, and so on. It is available for use as the CM8 hard macro. The S-module is designed to implement high-speed sequential functions within a single module.

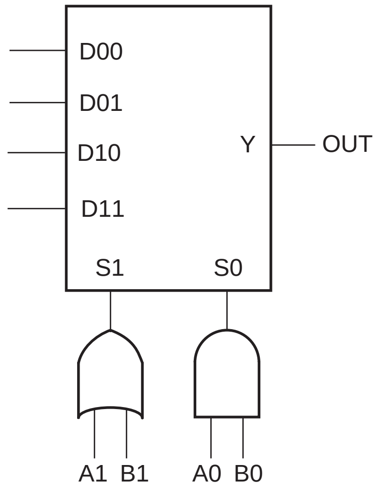


Figure 2-2 • **C-Module Diagram**

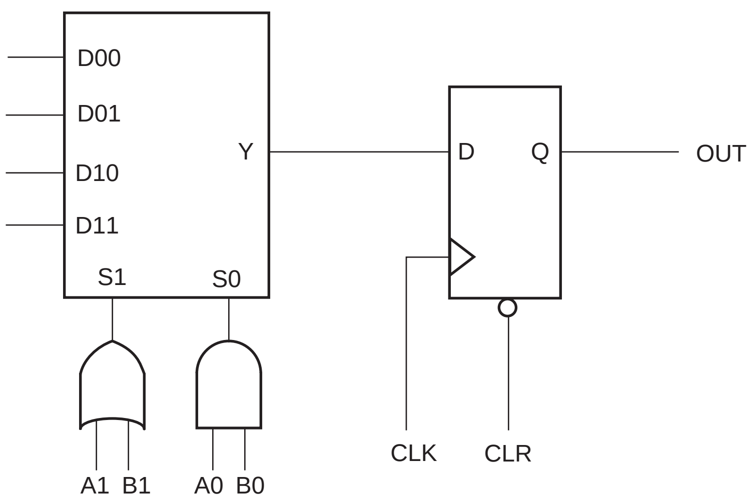


Figure 2-3 • **S-Module Diagram**

S-modules consist of a full C-module driving a flip-flop, which allows an additional level of logic to be implemented without additional propagation delay. It is available for use as the DFM8A/B and DLM8A/B hard macros. C-modules and S-modules are arranged in pairs called module-pairs. Module-pairs are arranged in alternating patterns and make up the bulk of the array. This arrangement allows the placement software to support two-module macros of four types (CC, CS, SC, and SS). The C-module implements the following function:

$$Y = !S1 * !S0 * D00 + !S1 * S0 * D01 + S1 * !S0 * D10 + S1 * S0 * D11 \quad \text{EQ 1}$$

where: S0 = A0 * B0 and S1 = A1 + B1

Horizontal Routing

Horizontal channels are located between the rows of modules and are composed of several routing tracks. The horizontal routing tracks within the channel are divided into one or more segments. The minimum horizontal segment length is the width of a module-pair, and the maximum horizontal segment length is the full length of the channel. Any segment that spans more than one-third the row length is considered a long horizontal segment. A typical channel is shown in Figure 2-7. Undedicated horizontal routing tracks are used to route signal nets. Dedicated routing tracks are used for the global clock networks and for power and ground tie-off tracks.

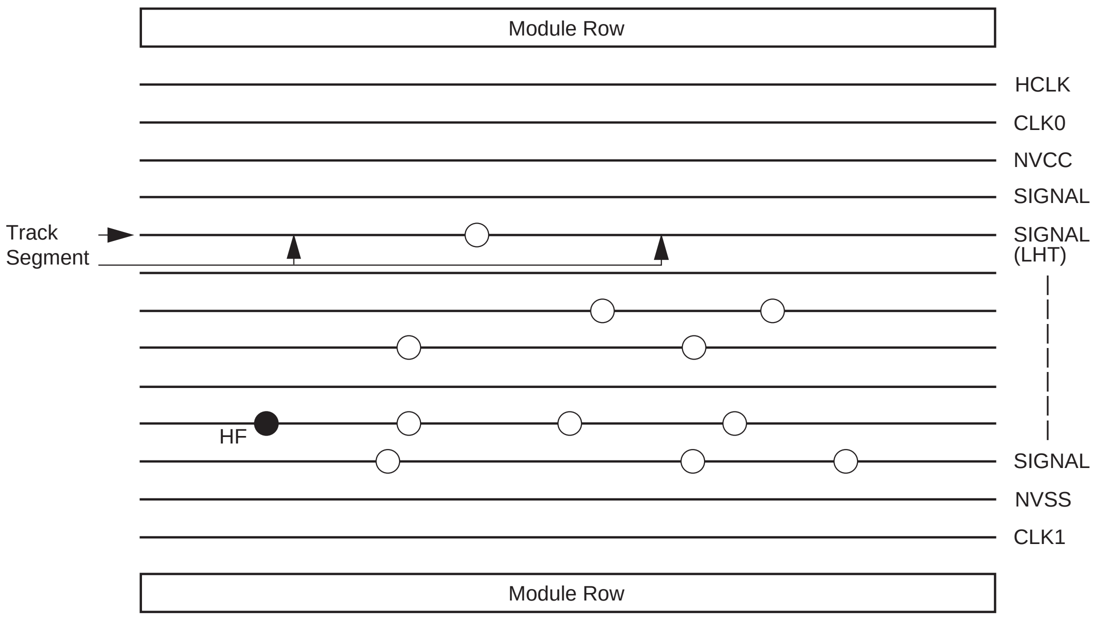


Figure 2-7 • **Horizontal Routing Tracks and Segments**

Vertical Routing

Other tracks run vertically through the modules. Vertical tracks are of three types: input, output, and long. Vertical tracks are also divided into one or more segments. Each segment in an input track is dedicated to the input of a particular module. Each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing. Each output segment spans four channels (two above and two below), except near the top and bottom of the array where edge effects occur. LVTs contain either one or two segments. An example of vertical routing tracks and segments is shown in Figure 2-8.

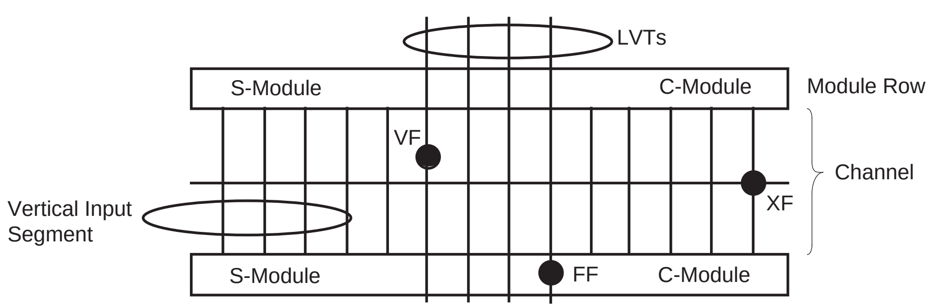


Figure 2-8 • **Vertical Routing Tracks and Segments**

Power Dissipation

P = [ICC standby + Iactive] * VCC * IOL * VOL * N + IOH* (VCC – VOH) * M

EQ 3

where:

ICC standby is the current flowing when no inputs or outputs are changing

Iactive is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source current.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M equals the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the design and on the system I/O. The power can be divided into two components: static and active.

Static Power Component

Microsemi FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated in Table 2-9 for commercial, worst case conditions.

Table 2-9 • **Standby Power Calculation**

ICC	VCC	Power
2 mA	5.25 V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

Active Power Component

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces and load device inputs.

An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by EQ 4.

$$\text{Power } (\mu W) = C_{EQ} * VCC^2 * F$$

EQ 4

Where:

C_{EQ} is the equivalent capacitance expressed in pF.

VCC is the power supply in volts.

F is the switching frequency in MHz.

***Table 2-11* • Fixed Capacitance Values for Microsemi FPGAs**

Device Type	r1, routed_Clk1	r2, routed_Clk2
A1415A	60	60
A14V15A	57	57
A1425A	75	75
A14V25A	72	72
A1440A	105	105
A14V40A	100	100
A1440B	105	105
A1460A	165	165
A14V60A	157	157
A1460B	165	165
A14100A	195	195
A14V100A	185	185
A14100B	195	195

***Table 2-12* • Fixed Clock Loads (s1/s2)**

Device Type	s1, Clock Loads on Dedicated Array Clock	s2, Clock Loads on Dedicated I/O Clock
A1415A	104	80
A14V15A	104	80
A1425A	160	100
A14V25A	160	100
A1440A	288	140
A14V40A	288	140
A1440B	288	140
A1460A	432	168
A14V60A	432	168
A1460B	432	168
A14100A	697	228
A14V100A	697	228
A14100B	697	228

Timing Derating

ACT 3 devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Table 2-15 **• Timing Derating Factor (Temperature and Voltage)**

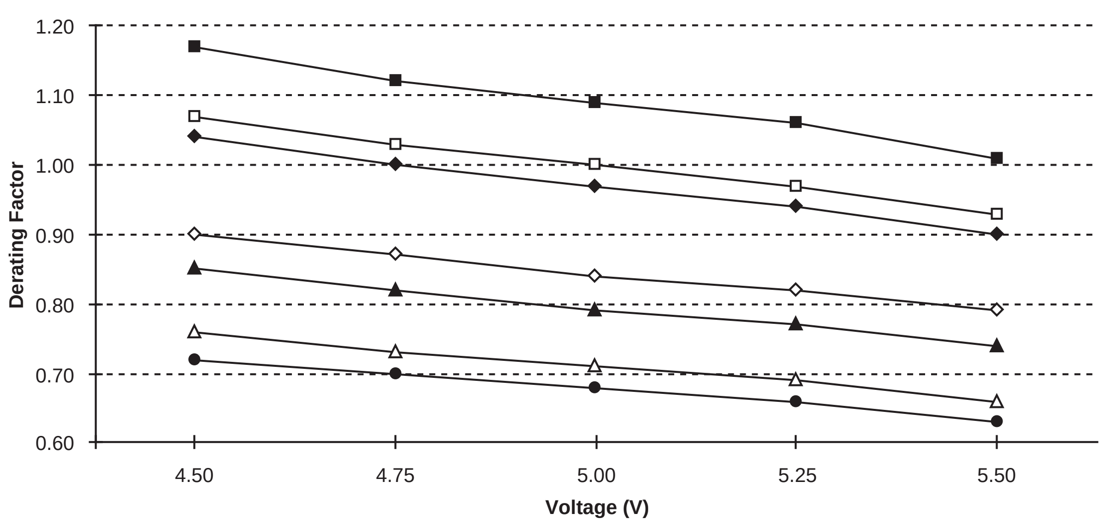
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	**Max.**	**Min.**	Max.
	0.66	1.07	0.63	1.17

Table 2-16 **• Timing Derating Factor for Designs at Typical Temperature (T_J = 25°C) and Voltage (5.0 V)**

(Commercial Maximum Specification) x	0.85

Table 2-17 **• Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)**

	–55	**–40**	**0**	**25**	**70**	**85**	**125**
4.50	0.72	0.76	0.85	0.90	1.04	1.07	1.117
4.75	0.70	0.73	0.82	0.87	1.00	1.03	1.12
5.00	0.68	0.71	0.79	0.84	0.97	1.00	1.09
5.25	0.66	0.69	0.77	0.82	0.94	0.97	1.06
5.50	0.63	0.66	0.74	0.79	0.90	0.93	1.01



Note: This derating factor applies to all routing and propagation delays.

Figure 2-18 **• Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)**

A1425A, A14V25A Timing Characteristics (continued)

Table 2-24 **• A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module – TTL Output Timing[1]		–3 Speed[2]		–2 Speed[2]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		6.5		7.5		8.5		10.0		13.0	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		6.5		7.5		8.5		10.0		13.0	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		7.5		7.5		9.0		10.0		13.0	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		6.7		7.5		8.5		10.0		13.0	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		6.7		7.5		9.0		10.0		13.0	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		8.9		8.9		10.7		11.8		15.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes: *

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A1440A, A14V40A Timing Characteristics (continued)

Table 2-28 **• A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module – TTL Output Timing[1]		–3 Speed[2]		–2 Speed[2]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		8.5		8.5		9.5		11.0		14.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.1		11.8		14.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A14100A, A14V100A Timing Characteristics

Table 2-34 • **A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C[1]**

Logic Module Propagation Delays[2]		–3 Speed[3]		–2 Speed[3]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t_{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t_{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays[4]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t_{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t_{SUD}	Latch Data Input Setup	0.5		0.6		0.8		0.8		0.8		ns
t_{HD}	Latch Data Input Hold	0.0		0.0		0.5		0.5		0.5		ns
t_{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t_{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t_A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f_{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. *VCC = 3.0 V for 3.3 V specifications.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn}$ or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
4. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A14100A, A14V100A Timing Characteristics (continued)

Table 2-35 **• A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		–3 Speed[1]		–2 Speed[1]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	1.2		1.4		1.5		1.8		1.8		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		1.0		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		1.0		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.5		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		2.0		2.0		2.0		ns

Notes: *

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

Pin Descriptions

CLKA Clock A (Input)

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

CLKB Clock B (Input)

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

GND Ground

LOW supply voltage.

HCLK Dedicated (Hard-wired) Array Clock (Input)

Clock input for sequential modules. This input is directly wired to each S-Module and offers clock speeds independent of the number of S-Modules being driven. This pin can also be used as an I/O.

I/O Input/Output (Input, Output)

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are tristated by the Designer Series software.

IOCLK Dedicated (Hard-wired) I/O Clock (Input)

Clock input for I/O modules. This input is directly wired to each I/O module and offers clock speeds independent of the number of I/O modules being driven. This pin can also be used as an I/O.

IOPCL Dedicated (Hard-wired) I/O Preset/Clear (Input)

Input for I/O preset or clear. This global input is directly wired to the preset and clear inputs of all I/O registers. This pin functions as an I/O when no I/O preset or clear macros are used.

MODE Mode (Input)

The MODE pin controls the use of diagnostic pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled high when required.

NC No Connection

This pin is not connected to circuitry within the device.

PRA Probe A (Output)

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

PRB Probe B (Output)

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDI Serial Data Input (Input)

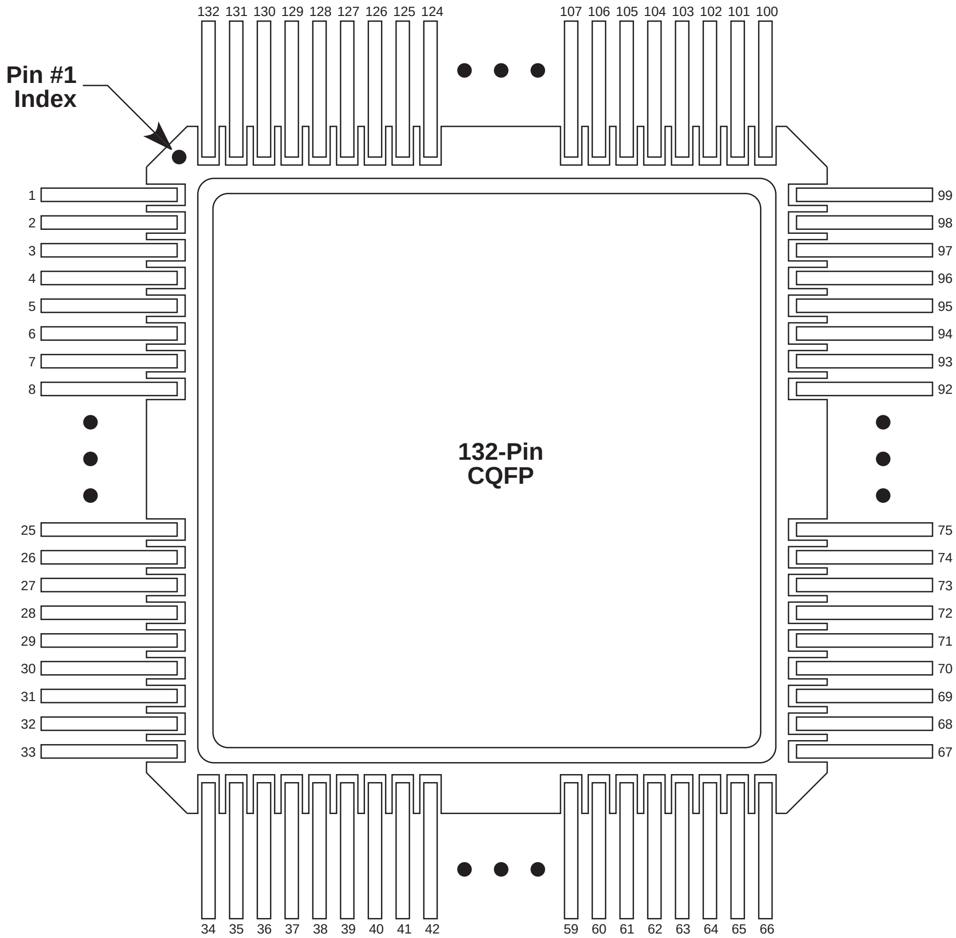
Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

PQ160			
Pin Number	A1425, A14V25 Function	A1440, A14V40 Function	A1460, A14V60 Function
92	NC	I/O	I/O
93	NC	I/O	I/O
98	GND	GND	GND
99	VCC	VCC	VCC
100	NC	I/O	I/O
103	GND	GND	GND
107	NC	I/O	I/O
109	NC	I/O	I/O
110	VCC	VCC	VCC
111	GND	GND	GND
112	VCC	VCC	VCC
113	NC	I/O	I/O
119	NC	I/O	I/O
120	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
121	GND	GND	GND
124	NC	I/O	I/O
127	NC	I/O	I/O
136	CLKA, I/O	CLKA, I/O	CLKA, I/O
137	CLKB, I/O	CLKB, I/O	CLKB, I/O
138	VCC	VCC	VCC
139	GND	GND	GND
140	VCC	VCC	VCC
141	GND	GND	GND
142	PRA, I/O	PRA, I/O	PRA, I/O
143	NC	I/O	I/O
145	NC	I/O	I/O
147	NC	I/O	I/O
149	NC	I/O	I/O
151	NC	I/O	I/O
153	NC	I/O	I/O
154	VCC	VCC	VCC
160	DCLK, I/O	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ132



Note: This is the top view

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

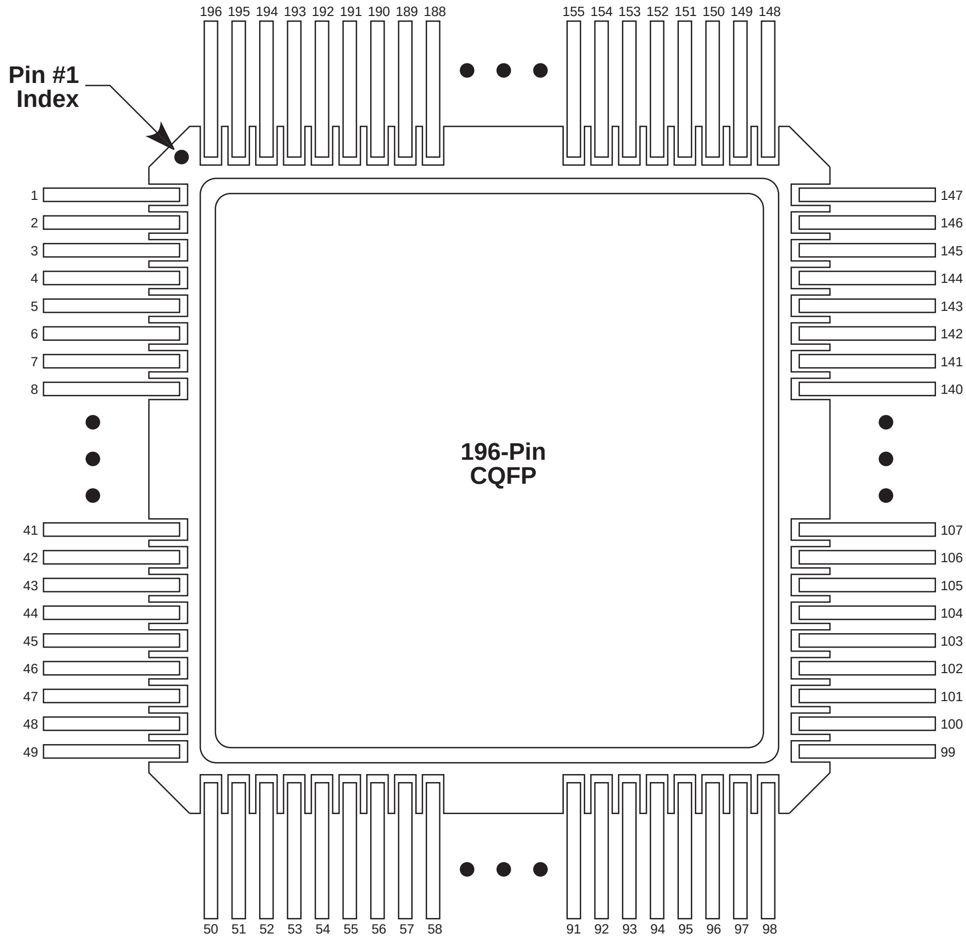
CQ132	
Pin Number	**A1425 Function**
1	NC
2	GND
3	SDI, I/O
9	MODE
10	GND
11	VCC
22	VCC
26	GND
27	VCC
34	NC
36	GND
42	GND
43	VCC
48	PRB, I/O
50	HCLK, I/O
58	GND
59	VCC
63	SDO
64	IOPCL, I/O
65	GND
66	NC

CQ132	
Pin Number	**A1425 Function**
67	NC
74	GND
75	VCC
78	VCC
89	VCC
90	GND
91	VCC
92	GND
98	IOCLK, I/O
99	NC
100	NC
101	GND
106	GND
107	VCC
116	CLKA, I/O
117	CLKB, I/O
118	PRA, I/O
122	GND
123	VCC
131	DCLK, I/O
132	NC

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ196

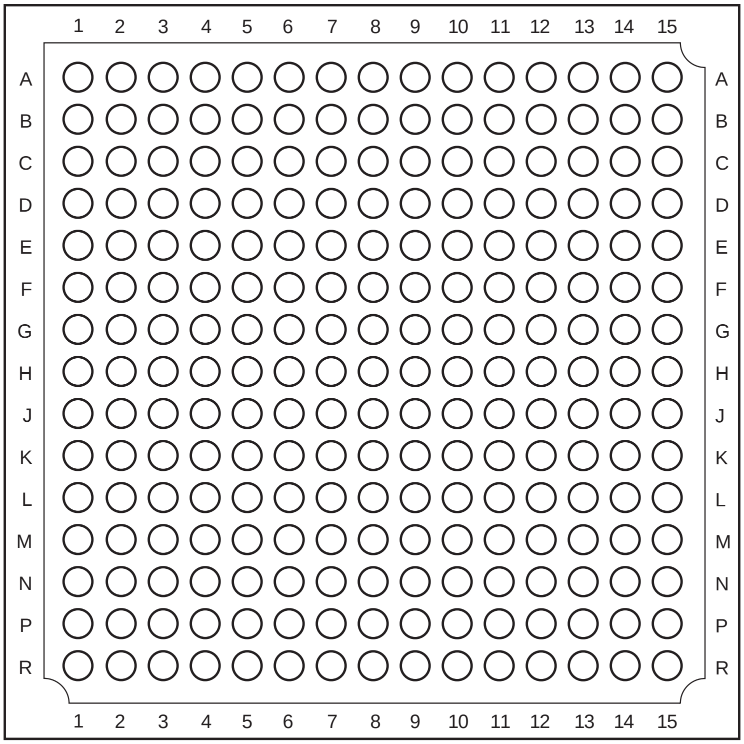


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

BG225



Note: *This is the top view.*

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

BG225	
A1460 Function	**Location**
CLKA or I/O	C8
CLKB or I/O	B8
DCLK or I/O	B2
GND	A1, A15, D15, F8, G7, G8, G9, H6, H7, H8, H9, H10, J7, J8, J9, K8, P2, R15
HCLK or I/O	P9
IOCLK or I/O	B14
IOPCL or I/O	P14
MODE	D1
NC	A11, B5, B7, D8, D12, F6, F11, H1, H12, H14, K11, L1, L13, N8, P5, R1, R8, R11, R14
PRA or I/O	A7
PRB or I/O	L7
SDI or I/O	D4
SDO	N13
VCC	A8, B12, D5, D14, E3, E8, E13, H2, H3, H11, H15, K4, L2, L12, M8, M15, P4, P8, R13

Notes:

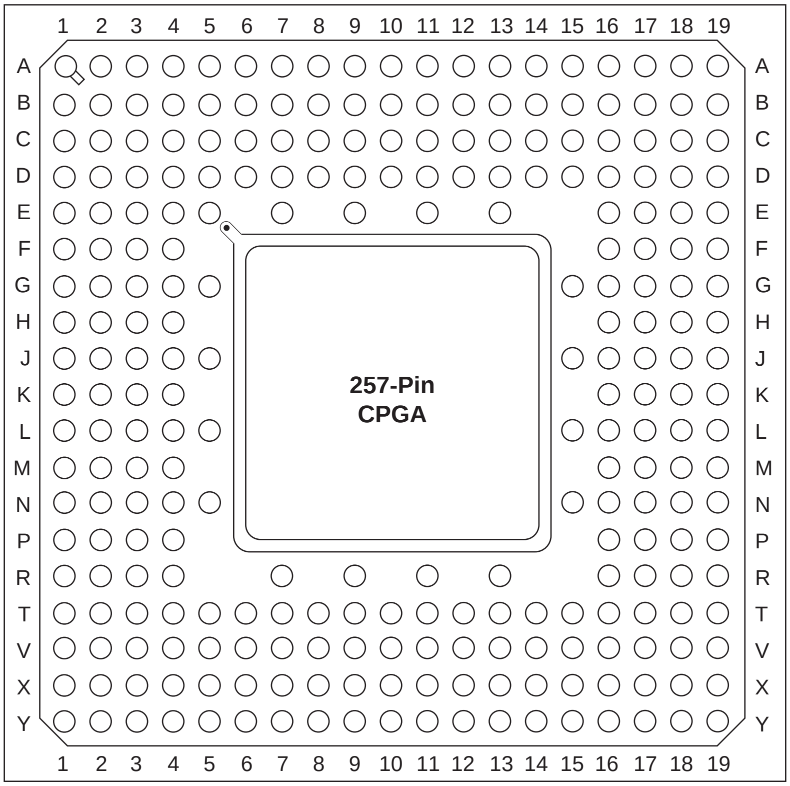
1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The BG225 package has been discontinued.

PG207	
A1460 Function	**Location**
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG257



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx